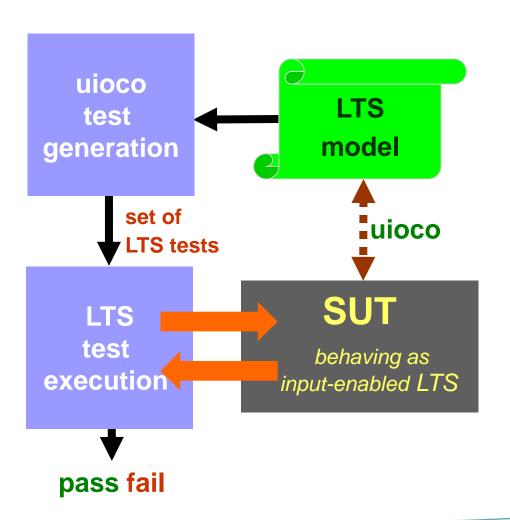
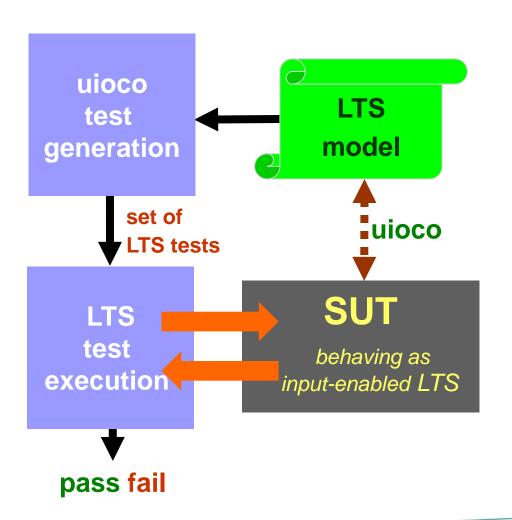
A Theory of Model-Based Testing with Labelled Transition Systems

Test Generation for uioco



- specification model
- system under test (SUT)
- SUT model
- conformance uioco
- test cases
- test generation
- test execution
- test result analysis
- sound & exhaustive



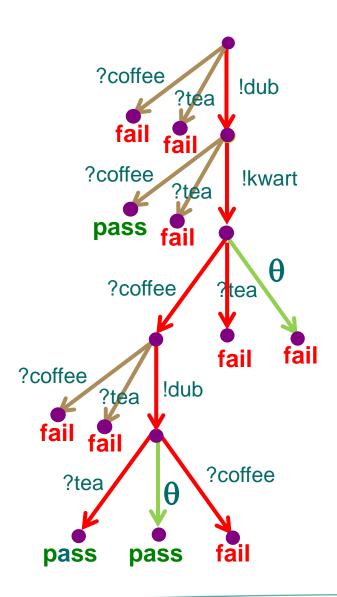
- specification model
- system under test (SUT)
- SUT model
- conformance uioco
- test cases
- test generation
- test execution
- test result analysis
- sound & exhaustive

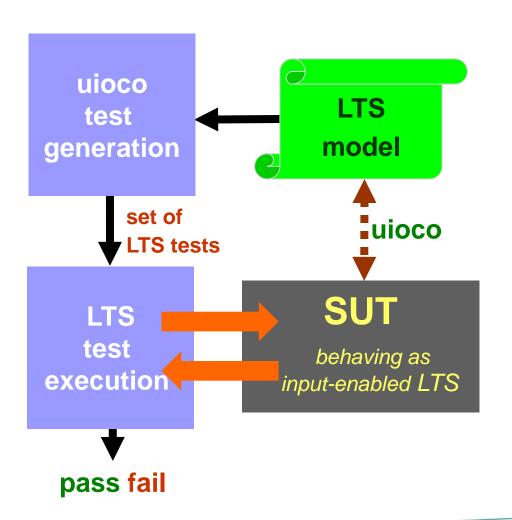
Test Cases

model of a test case

- = labelled transition system
- labels in $L_I \cup L_U \cup \{\theta\}$
- 'quiescence' / 'time-out' label θ
- tree-structured
- finite, deterministic
- sink states pass and fail
- from each state ≠ pass, fail :
 - either one input !a and all outputs ?x
 - or all outputs $\mathbf{?x}$ and $\mathbf{\theta}$



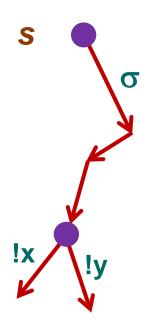


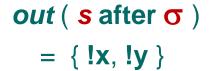


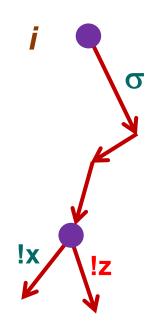
- specification model
- system under test (SUT)
- SUT model
- conformance uioco
- * test cases
- test generation
- test execution
- test result analysis
- sound & exhaustive

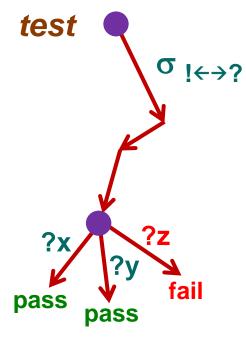
Test Generation

i uioco s = def $\forall \sigma \in Utraces(s): out(i after <math>\sigma) \subseteq out(s after \sigma)$



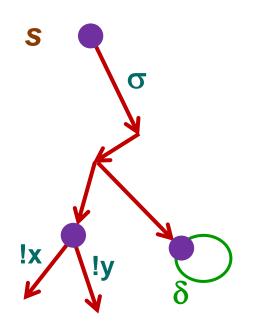


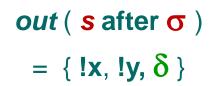


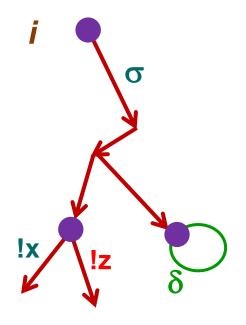


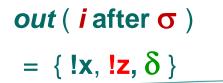
Test Generation

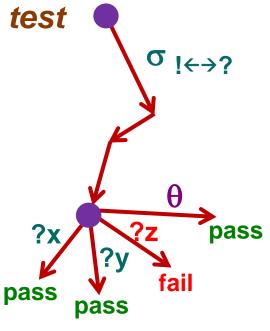
i uioco s = def $\forall \sigma \in Utraces(s): out(i after <math>\sigma) \subseteq out(s after \sigma)$











out (test after σ)
= { !x, !y, !z, θ }

Test Generation Algorithm: uioco

Algorithm to generate a test case t(s)

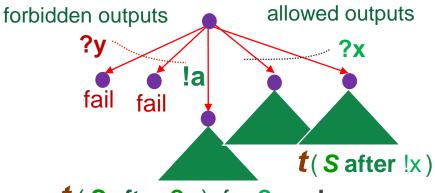
from a transition system state set S, with $S \neq \emptyset$, and initially $S = S_0$ after S.

Apply the following steps recursively, non-deterministically:

1 end test case

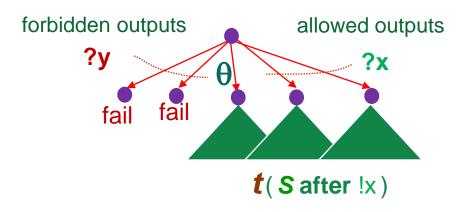
pass

2 supply input !a



t (S after ?a), for ? $a \in L_I$ and not S refuses {?a}

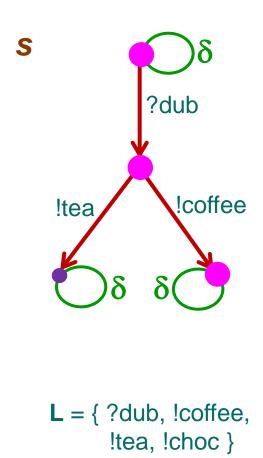
3 observe all outputs

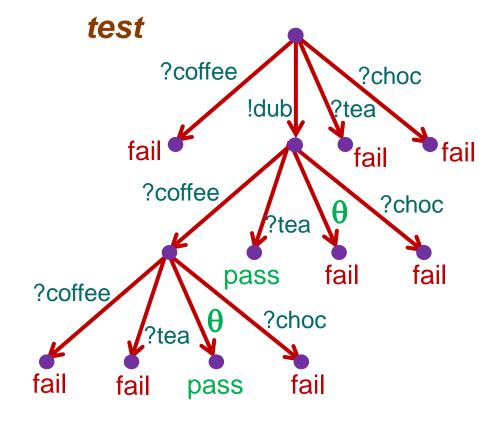


allowed outputs (or δ): $\mathbf{x} \in out(\mathbf{S})$

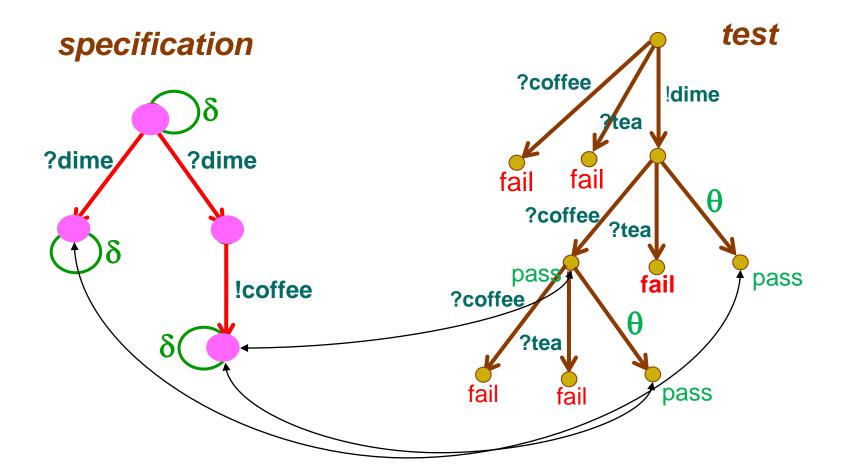
forbidden outputs (or δ): !y $\notin out(S)$

Example: *uioco* Test Generation





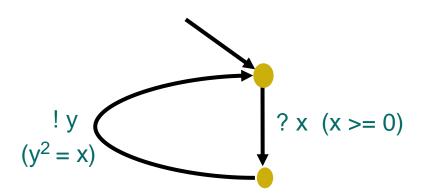
Example: *uioco* Test Generation



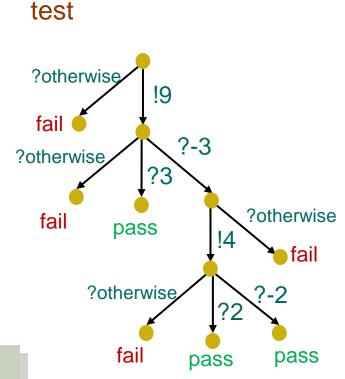
Example: *uioco* Test Generation

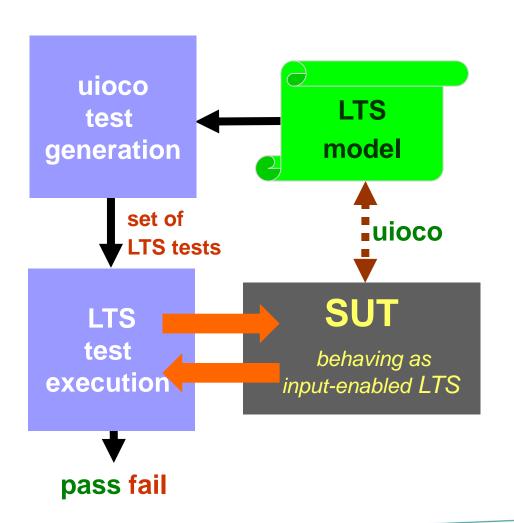
Equation solver for $y^2=x$

specification s



To cope with non-deterministic behaviour, tests are not linear traces, but trees





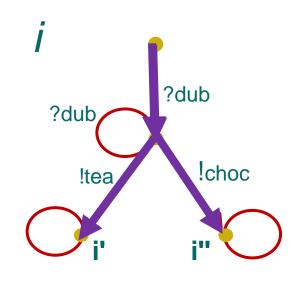
- specification model
- system under test (SUT)
- SUT model
- conformance uioco
- * test cases
- test generation
- test execution
- test result analysis
- sound & exhaustive

Test Execution

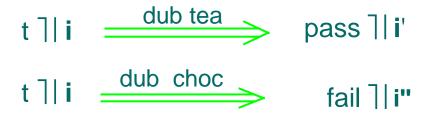
Test execution = all possible parallel test runs of test t with implementation i going to state pass or fail

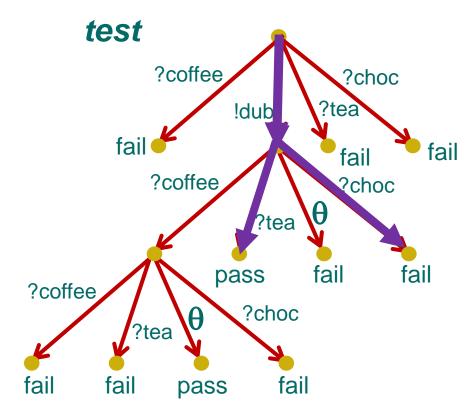
Test run :
$$t \mid i \xrightarrow{\sigma} pass \mid i' \text{ or } t \mid i \xrightarrow{\sigma} fail \mid i'$$

Example: Test Execution



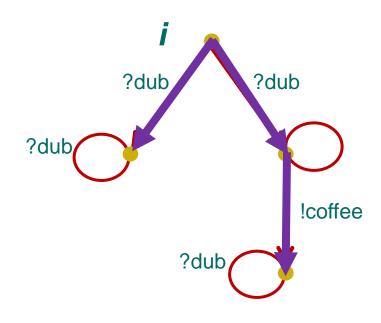
Two test runs:





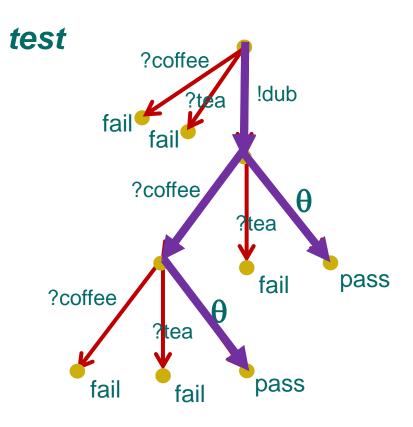
i fails t

Example: Test Execution



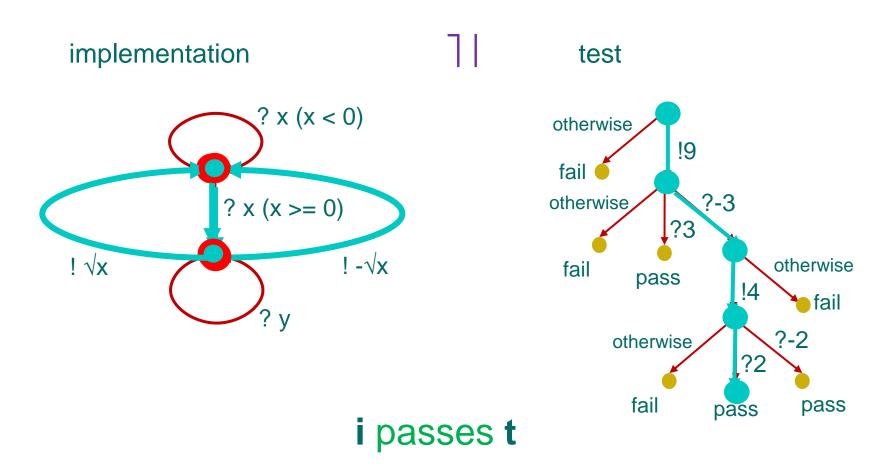
Two test runs:

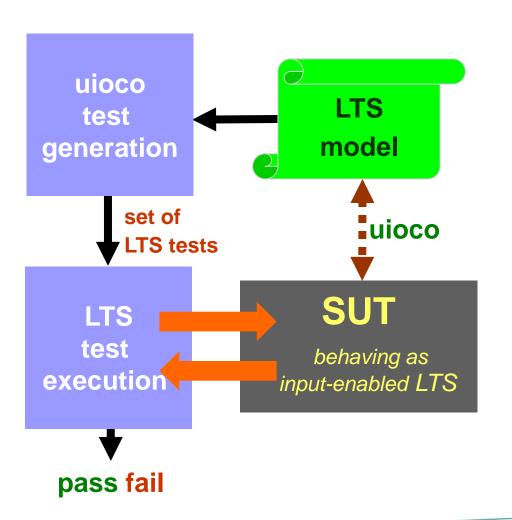
t
$$\exists$$
 i \exists dub θ pass \exists i' t \exists i \exists dub coffee θ pass \exists i'



i passes t

Example: Test Execution





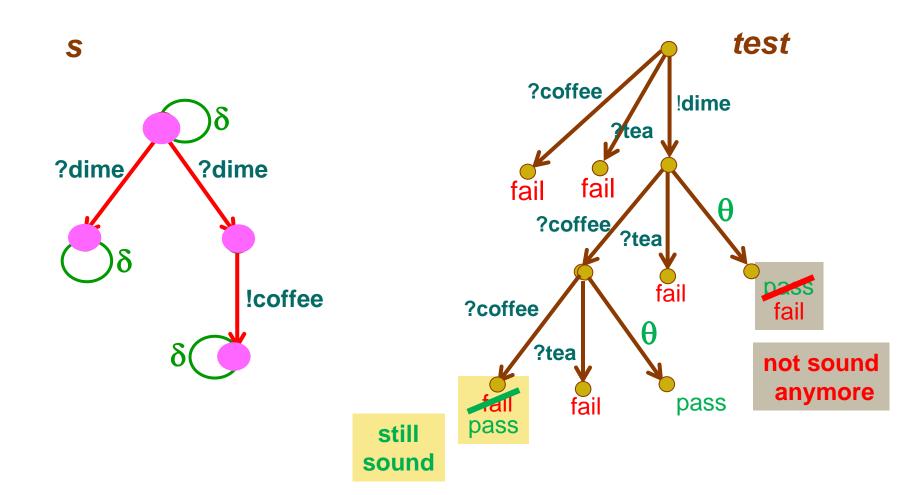
- specification model
- system under test (SUT)
- SUT model
- conformance uioco
- * test cases
- test generation
- test execution
- test result analysis
- sound & exhaustive

Validity of Test Generation

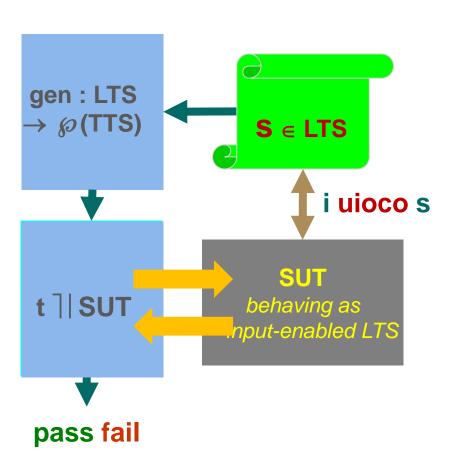
For every test **t** generated with algorithm we have:

- Soundness:
 - t will never fail with correct implementation
 - i uioco s implies i passes t
- Exhaustiveness:
 each incorrect implementation can be detected
 with a generated test t
 - i uico s implies 3 t: i fails t

Soundness and Exhaustiveness



MBT with uioco is Sound and Exhaustive

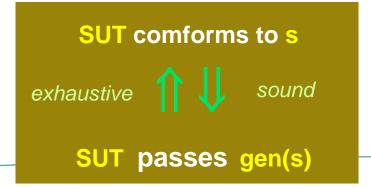


Testability assumption:

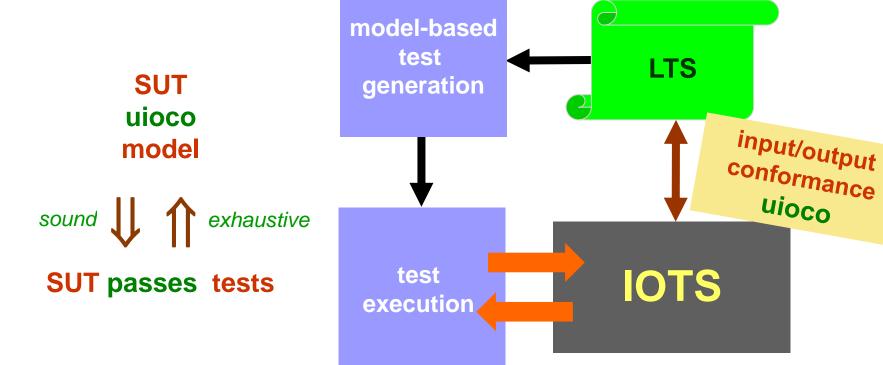
 $\forall \text{SUT} \in \text{IMP} . \exists m_{\text{SUT}} \in \text{IOTS} .$ $\forall t \in \text{TESTS} .$ $\text{SUT passes } t \Leftrightarrow m_{\text{SUT}} \text{ passes } t$

Prove soundness and exhaustiveness:

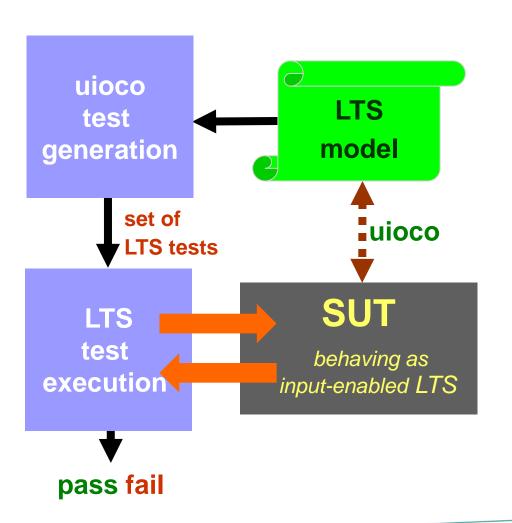
 $\forall m \in IOTS$. $(\forall t \in gen(s) . m passes t)$ $\Leftrightarrow m uioco s$



MBT: Model-Based Testing



pass fail



- specification model
- system under test (SUT)
- SUT
- conformance dioco
- test cas
- test generation
- * test execution
- test result analysis
- sound & exhaustive